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ADVANCED MATERIALS INTERFACES

Supporting Information

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Work Function Modification via Combined Charge-Based Through-Space Interaction and Surface Interaction

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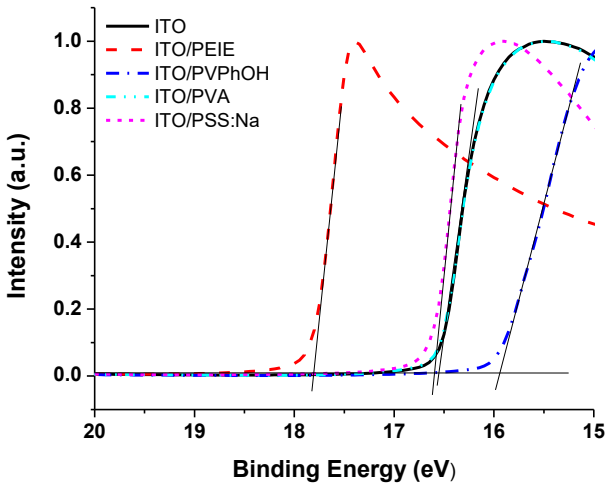


Figure S1. UPS spectra (He I) of ITO (black solid line), PEIE (red dashed line), PVPhOH (blue dash-dotted line), PVA (cyan short dashed line), PSS:Na (magenta dotted line) showing the onset of the secondary electron cutoff.

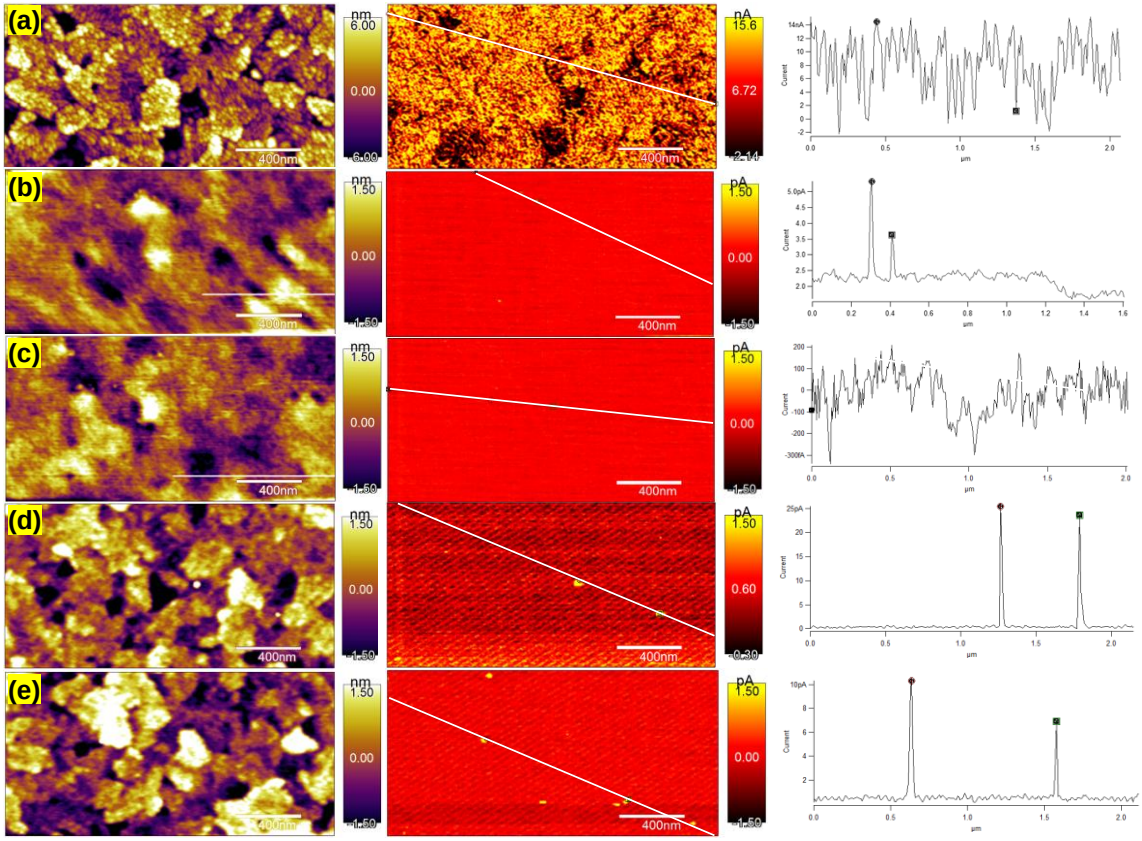


Figure S2. C-AFM topography (left column), its corresponding current map (middle column), and line profile of current map along a white solid line shown in each current map (right column) of (a) ITO substrate, PS thin film deposited on ITO substrates at a spinning speed of (b) 1000 rpm, (c) 2000 rpm, (d) 4000 rpm, and (e) 6000 rpm.

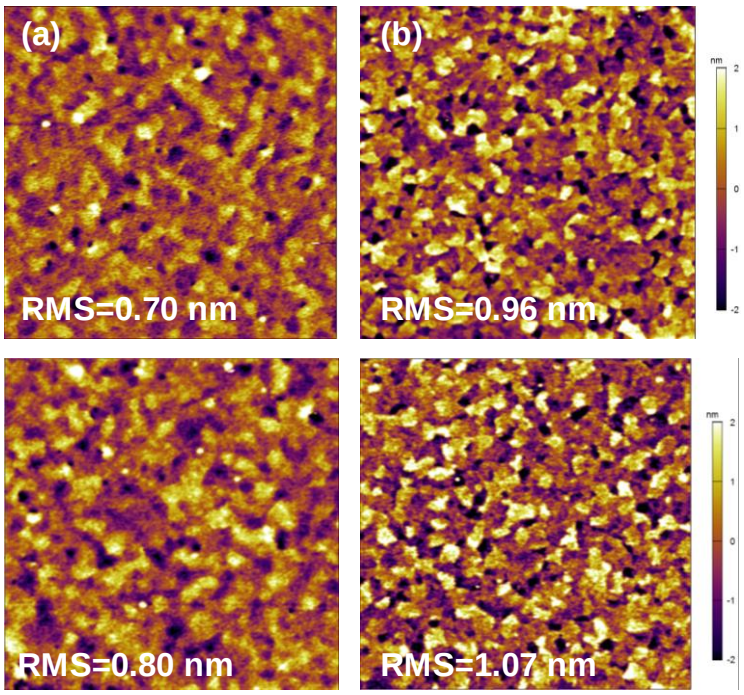


Figure S3. AFM topography of PS thin films deposited on ITO substrates at a spinning speed of (a) 1000 rpm, and (b) 6000 rpm before (top) and after (bottom) spincast of 2-methoxy ethanol. The scan area is 5x5 μm^2.

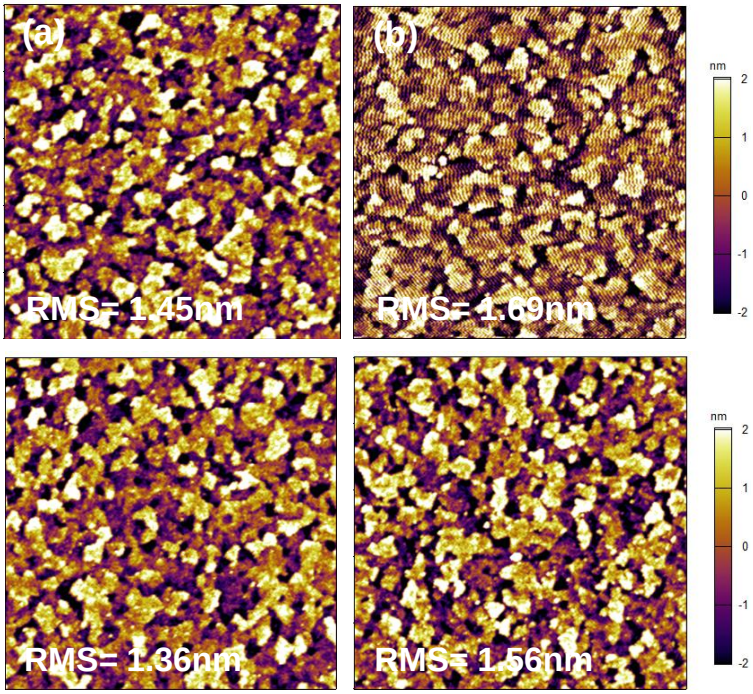


Figure S4. AFM topography of PVA thin films deposited on ITO substrates at a spinning speed of (a) 1000 rpm, and (b) 6000 rpm before (top) and after (bottom) spincast of 2-methoxy ethanol. The scan area is 5x5 μm^2.